Search Notes

1	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/724,717	SU, WEN-WEI	
E	Examiner	Art Unit	
	John A. Tweel, Jr.	2636	

	SEARCHED					
Class	Subclass	Date	Examiner			
340	539.11	6/7/2005	JAT _.			
	514	6/7/2005	JAT			
	605	6/7/2005	JAT			
	603	6/7/2005	JAT			
702	188	6/7/2005	JAT			

INT	TERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
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